

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/815,843	AHN ET AL.	
		Examiner	Art Unit	
		A. Sefer	2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,678,018	01-2004	Park et al.	349/43
	B	US-2002/0067455	06-2002	Komatsu, Hiroshi	349/141
	C	US-6,531,346	03-2003	Kim, Ik Soo	438/149
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 03/001606	01-2003	PCT	Byun et al	
	O	WO 03/036374	05-2003	PCT	Lee et al	
	P	JP 2003-195784	07-2003	Japan	Chiyabara et al.	
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.